



LG Fuel Cell Systems SOFC Technology and SECA Program Update

2014 SECA Workshop, 22 July 2014

Richard Goettler

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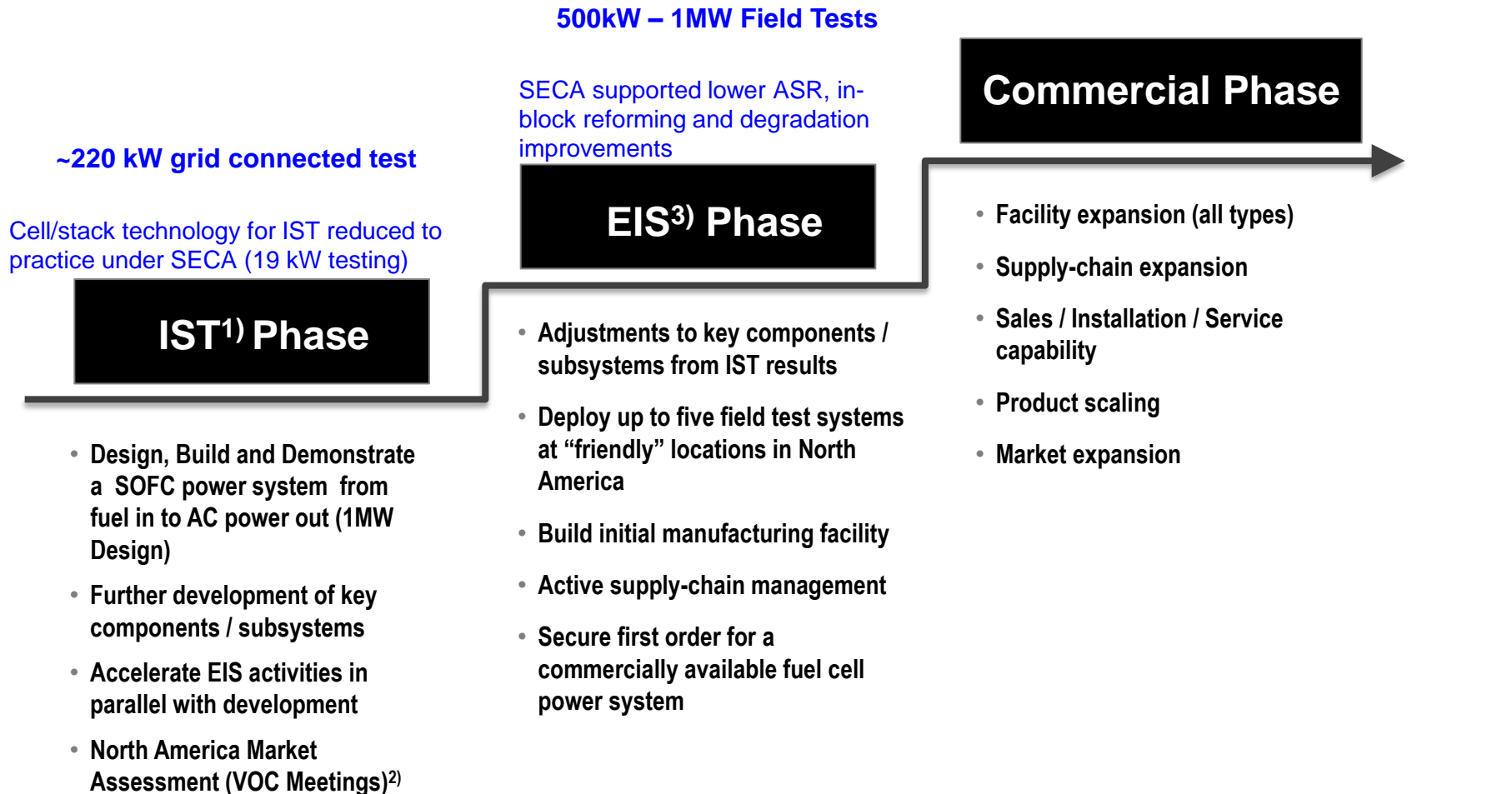
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Outline

- **LGFCs Business Activities - 220 kW test**
- **Degradation Mechanisms and Mitigation**
 - Cathode
 - Anode
 - Primary Interconnect
- **Cell-Stack changes for lower cost**
- **Strip Reliability**
 - Probability of failure predictions
 - Residual strength of substrates
- **Block Testing Update**

Phases of the business supported by SECA



¹⁾ IST : Integrated String Test

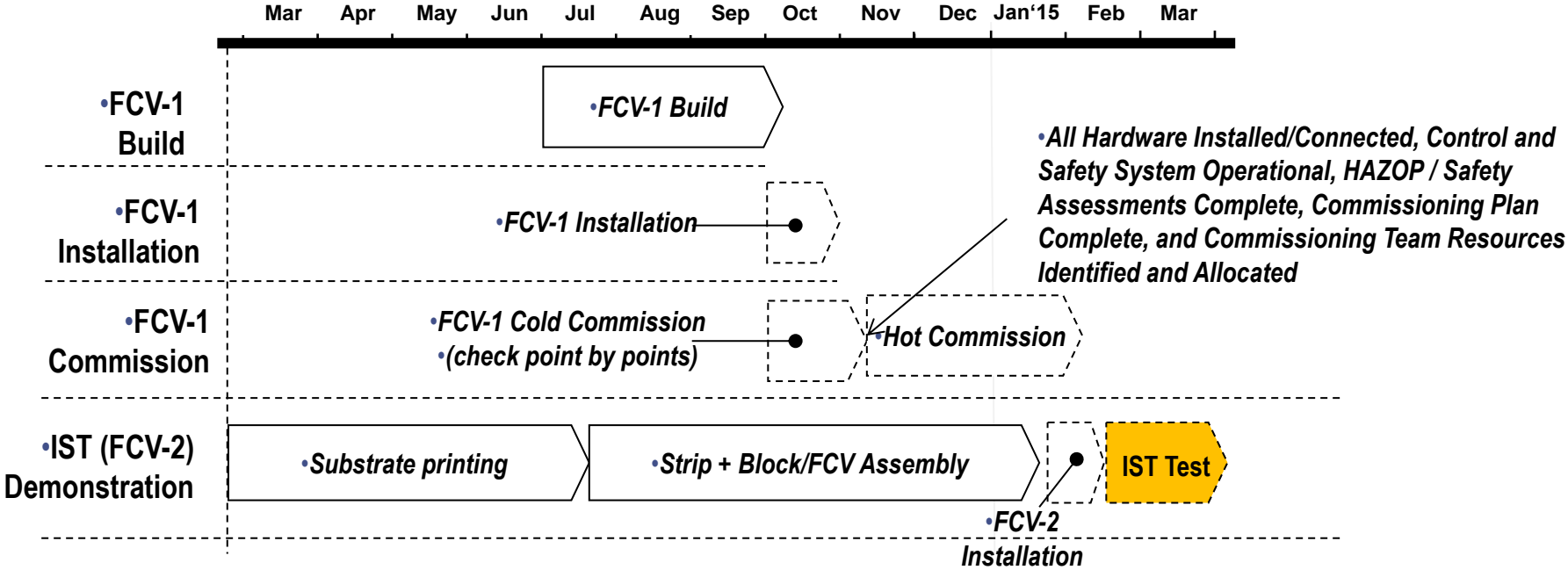
²⁾ VOC : Voice of the Customer

³⁾ EIS : Entry Into Service

LGFCS Integrated String Test Schedule

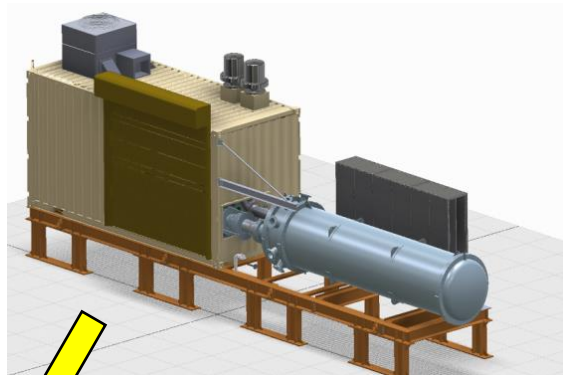
2014 Key Program Milestones Update

- ❑ Fuel Cell Vessel 1 (FCV-1): emulator blocks plus 1 active block for systems commissioning
- ❑ Fuel Cell Vessel 2 (FCV-2): fully loaded with active block for 220 kW



Commissioning of IST Subsystems is Progressing

- ✓ Fuel Processor commissioning completed
- ✓ FCV1 turbogenerator assembly under test, controls system completed
- ✓ FCV2 turbogenerator under test
- ✓ Block assembly for FCV1 in progress
- ✓ All substrates printed for FCV2, strip build underway
- ✓ Power electronics installed, grid connected, commissioning starting

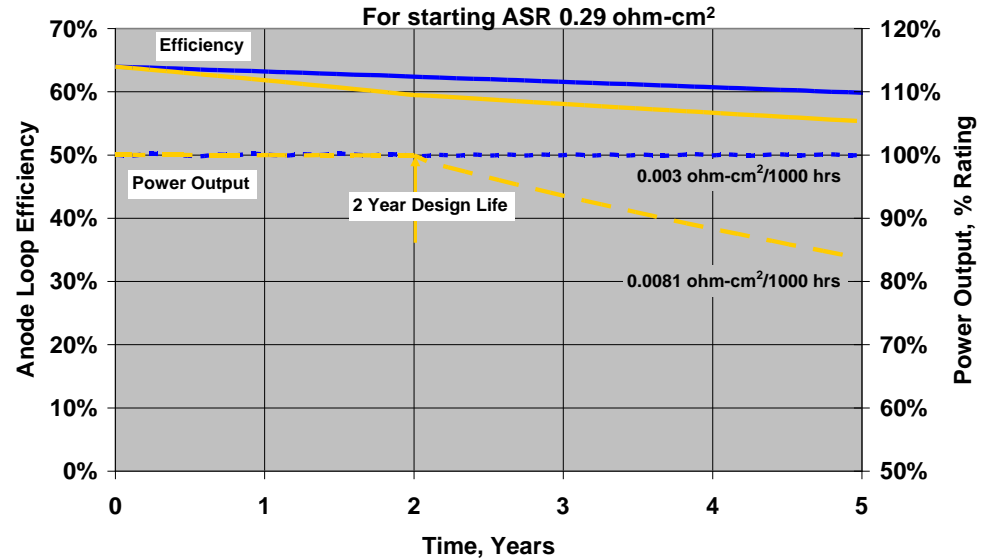


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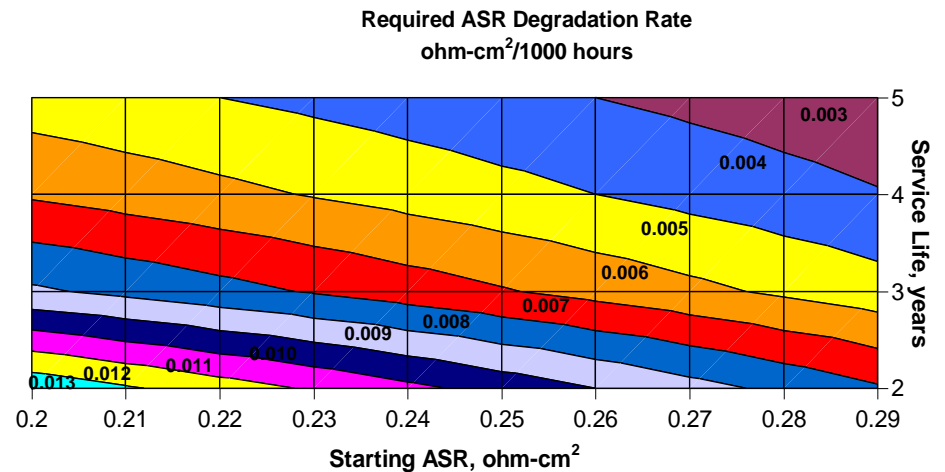
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Product Durability Strategy

- End of Life ASR = 0.42 ohm-cm² to meet efficiency requirement
- Assumes constant power over service life

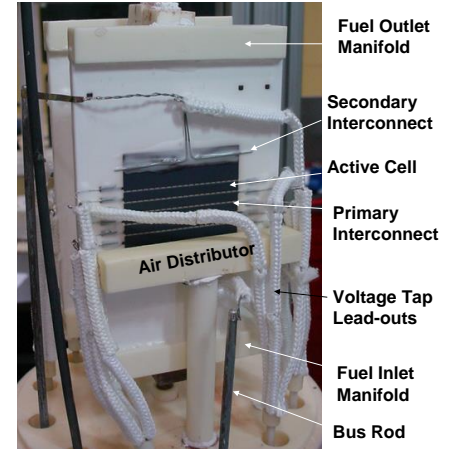


- Degradation rate target based on starting ASR and required stack life to meet cost
- Lifetime improved by reducing degradation mechanisms and/or lowering initial ASR

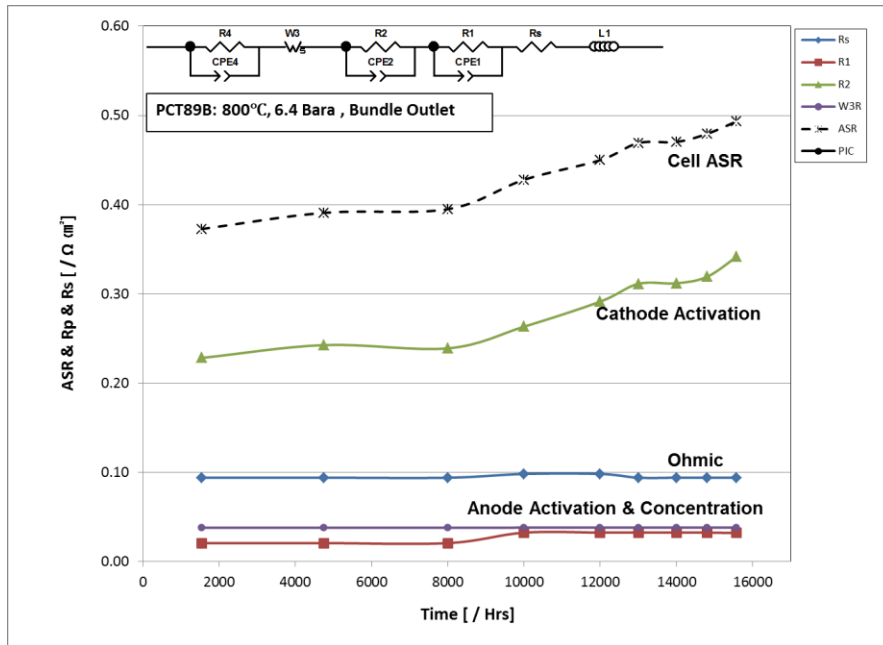


Ongoing durability testing at pentacell scale used to understand degradation contributions

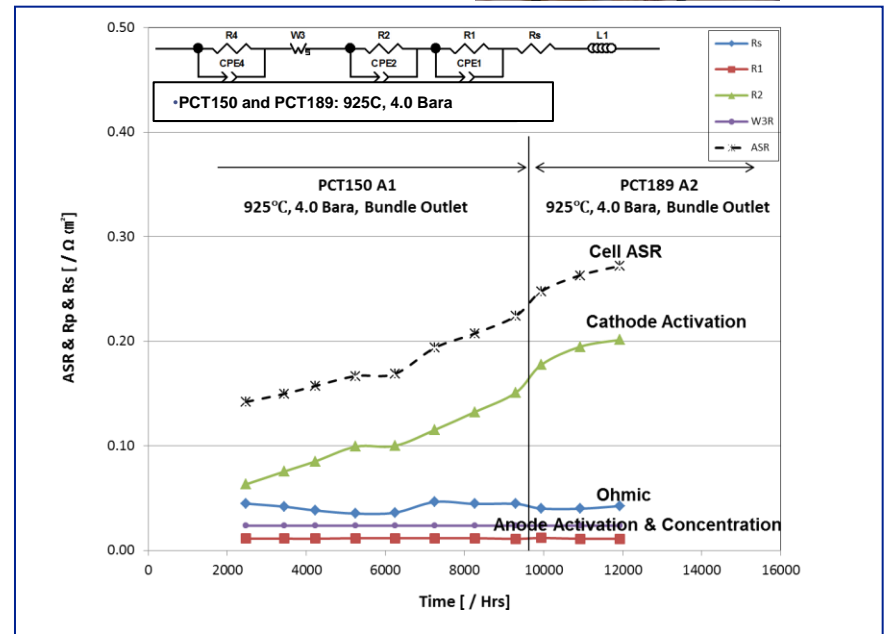
- Impedance measured at ~ 1000 hour intervals
- Resistance, capacitance, and Warburg elements to represent behavior
- Estimates of degradation contributions can then be charted over the life of the test
- **Cathodic mechanisms dominate**



800C



925C

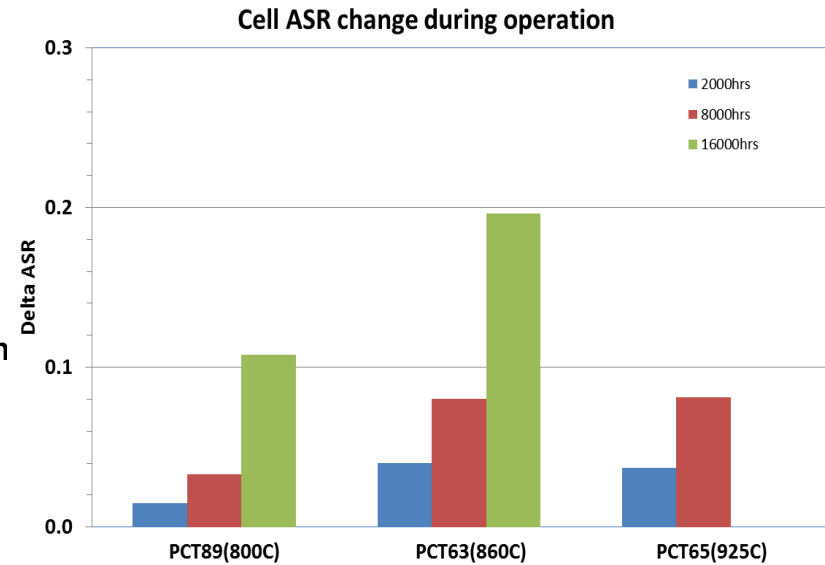
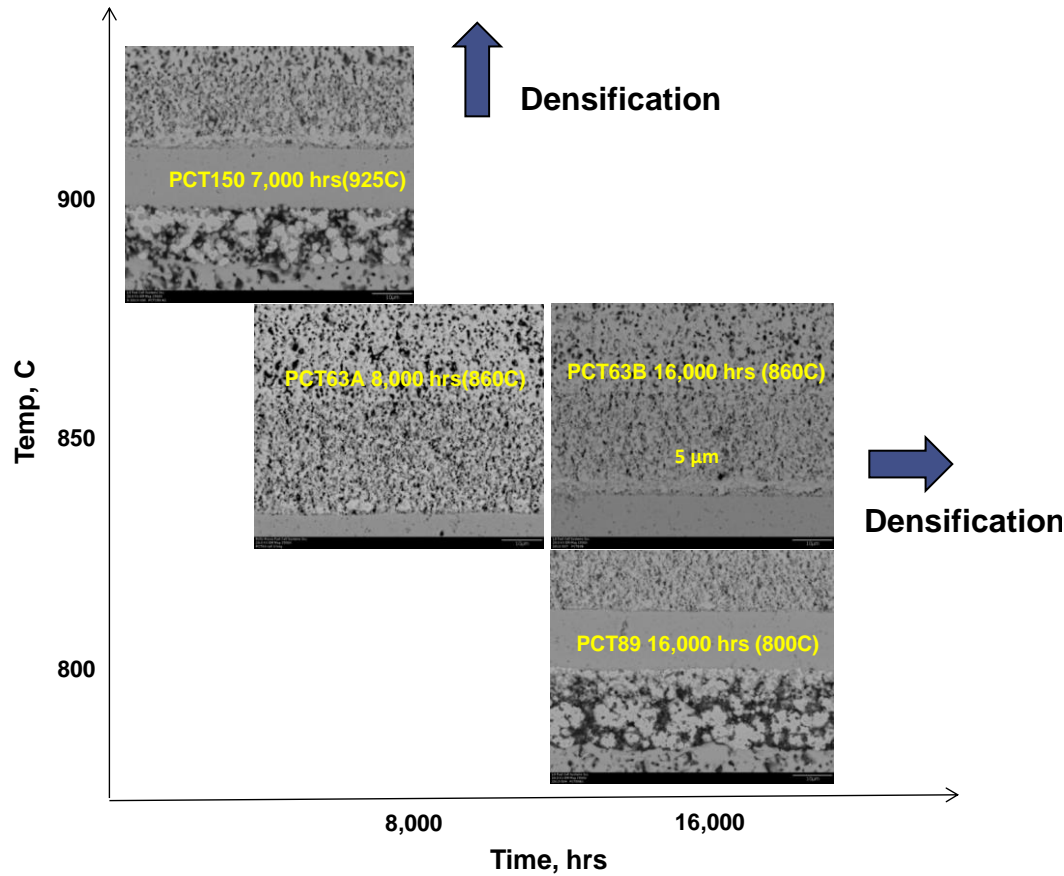


Cathode Degradation Mechanisms

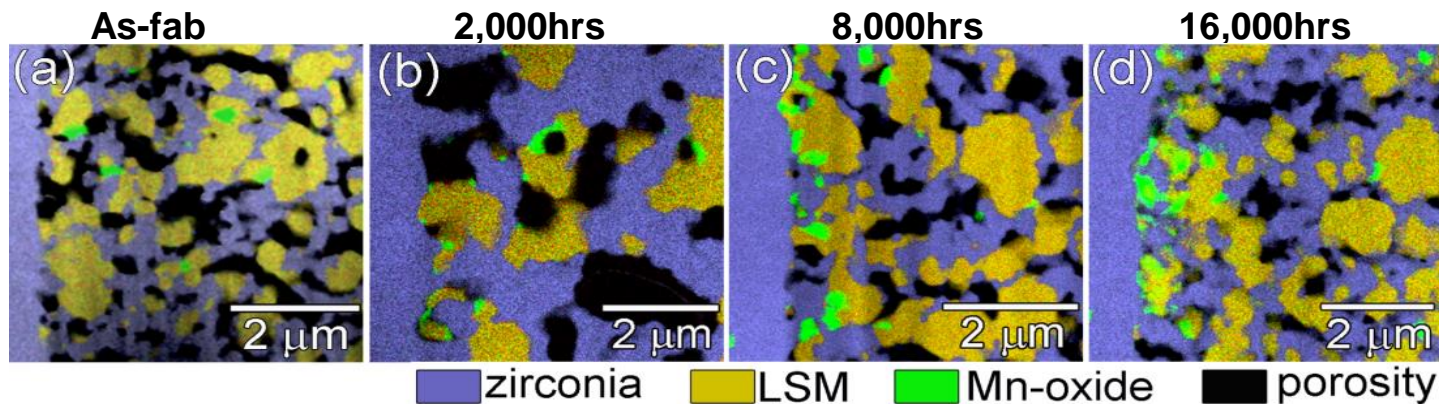
- Localized densification near electrolyte interface
- MnO_x segregation and/or migration
- MnO_x valence changes
- Moisture effect
- Cr effect
- Ionic phase degradation
- Material diffusion

Cathode Densification vs. Testing Conditions

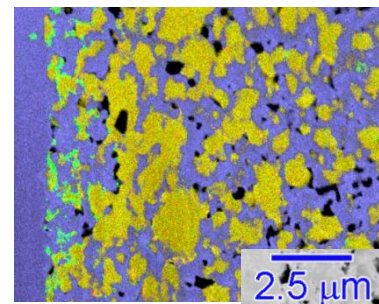
- Kinetics is a key factor for baseline LSM cathode densification



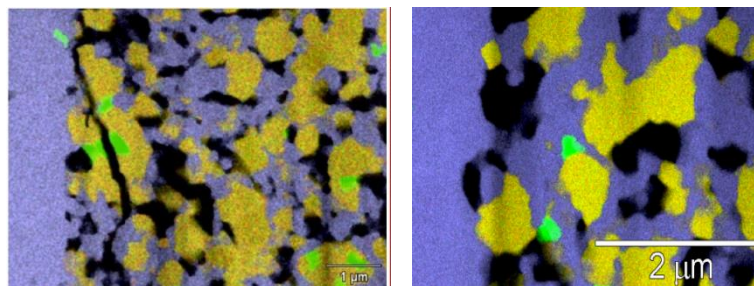
MnO_x Segregation/Migration Observed Across Temp. Range



800C



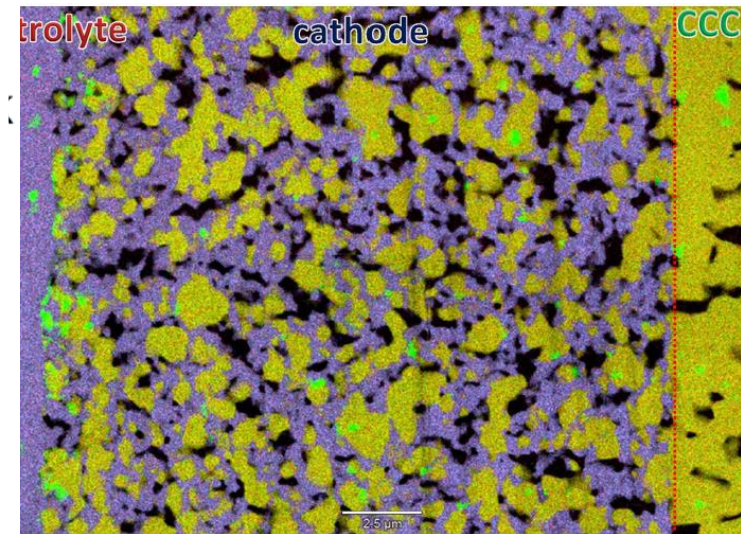
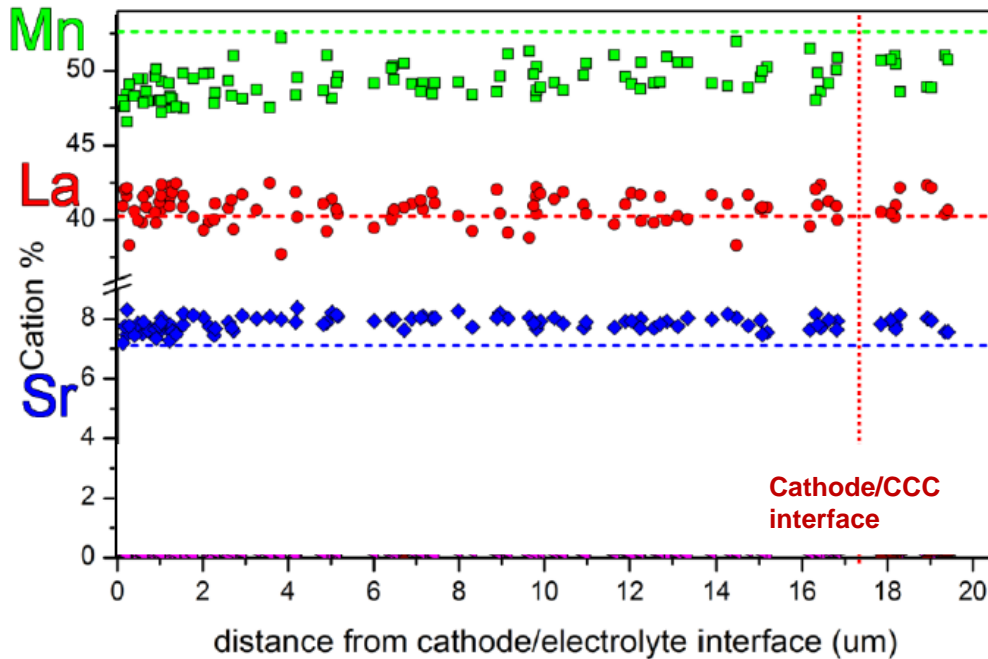
860C



900 -
925C

Minor amount of Mn exsolutes from LSM near interface

- Data from baseline LSM cathode
- Tested at 800°C for 16,000 hours under simulated system conditions

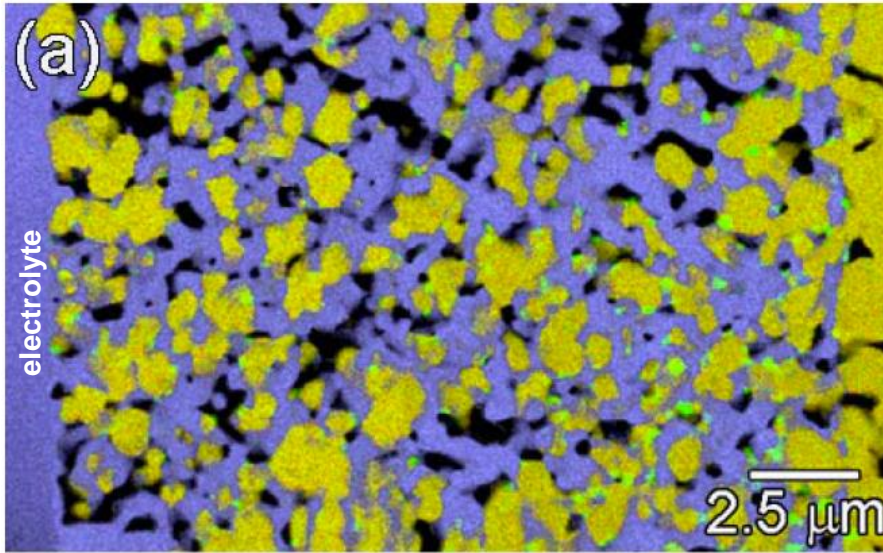


TEM image

MnO_x accumulation at interface not observed under OCV

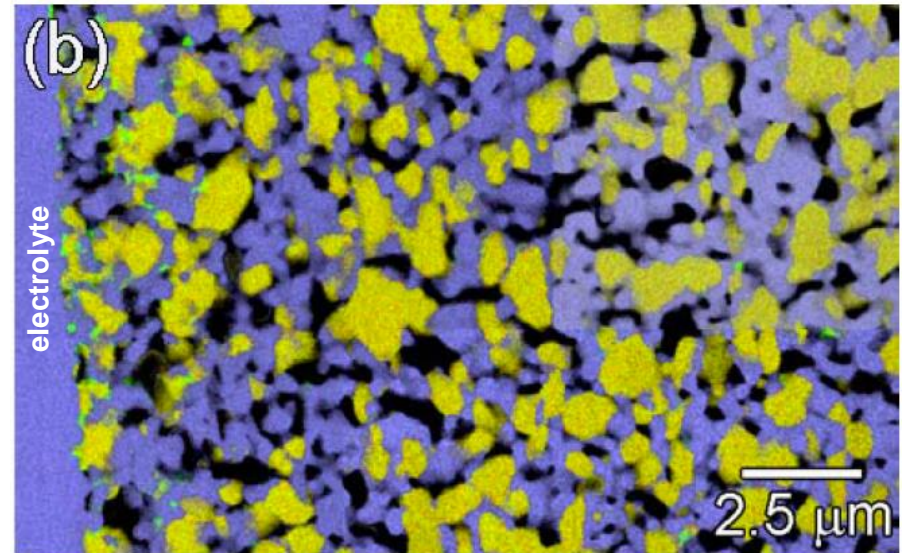
Reference cell w/o current load

- MnO_x at cathode/CCC interface



Active cell with current load

- MnO_x at electrolyte
- MnO_x elimination from bulk cathode

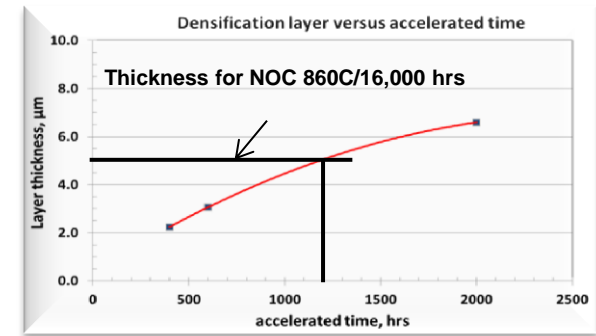


- Tested ~5000 hrs at 925°C and 4 bar

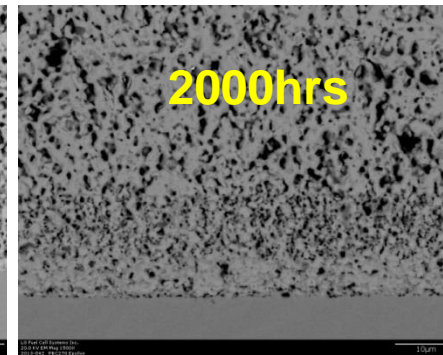
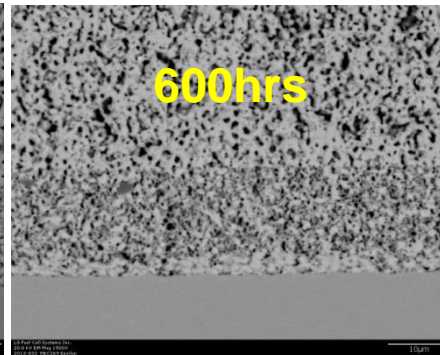
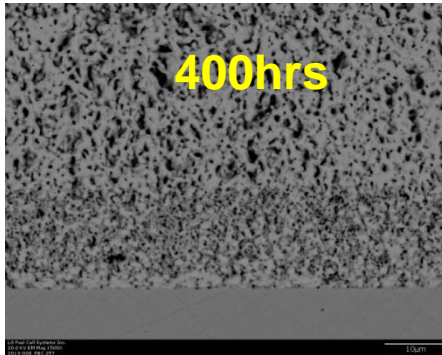


Accelerated Testing of Densification Mechanism

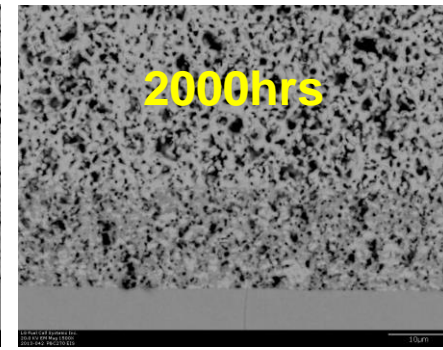
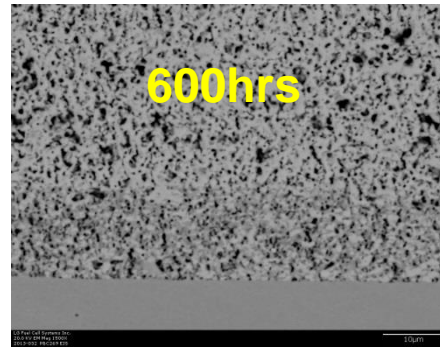
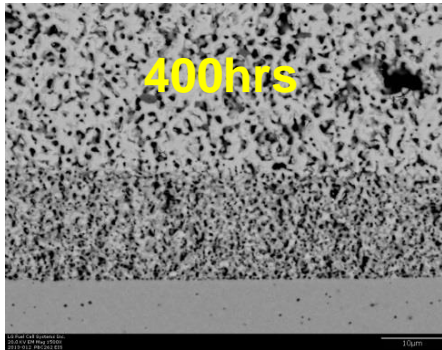
- Symmetric button cell tested under selected conditions to accelerate densification
- 860C, 16000 hr densification at NOC matched in 1200 hours accelerated



Baseline



Candidate

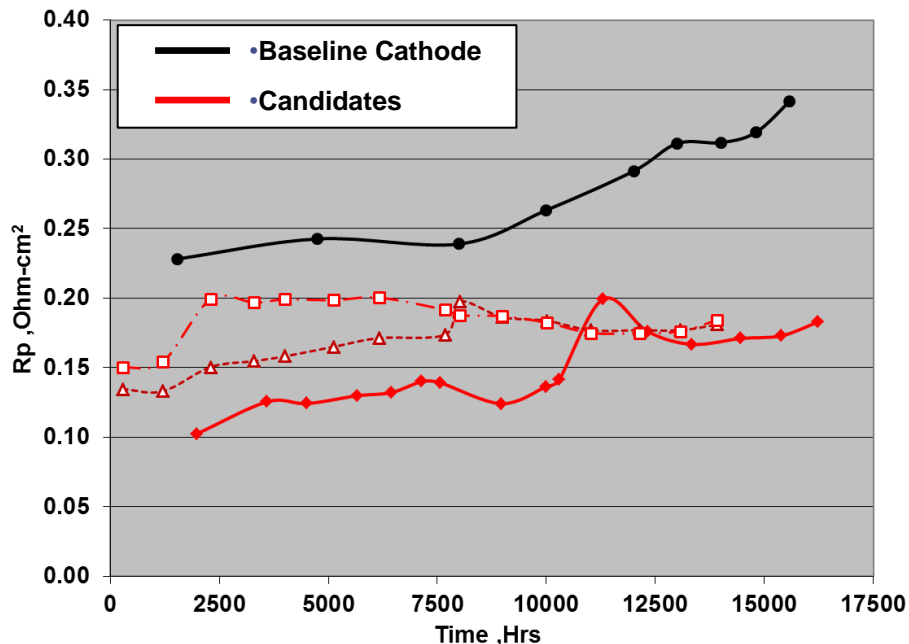


Footer

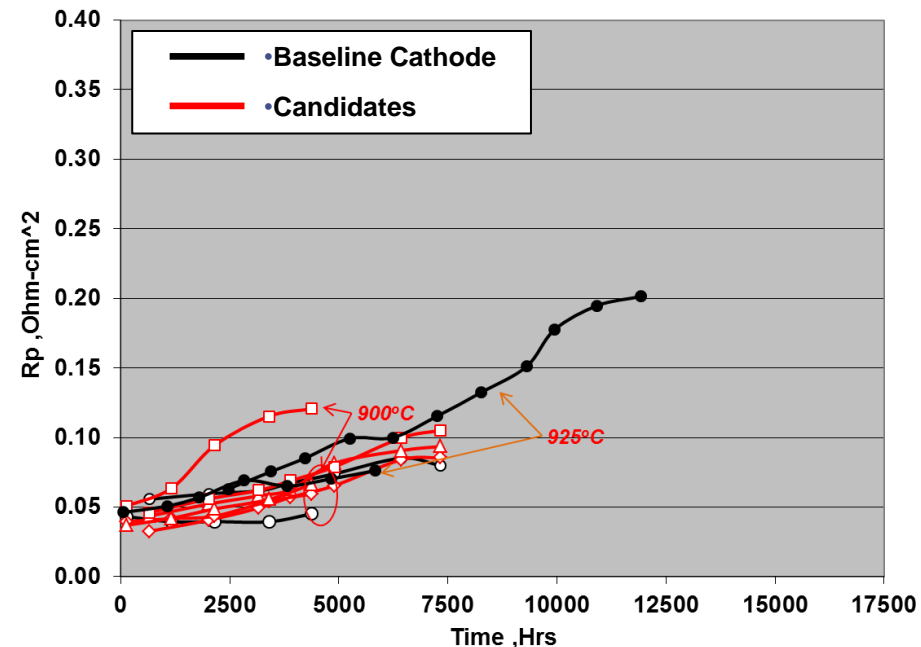
Long-term cathode material studies ongoing at different temperatures

- Candidate EIS cathodes show benefit at low temperature, similar degradation rates at high temperature
- Still seeking understanding of major degradation mechanisms across temperature ranges
 - Densification not a major contributor at low temp.
 - Further documenting the variation of MnO_x as function of temp. and LSM cathode composition

Cathode Rp Comparison (800°C)



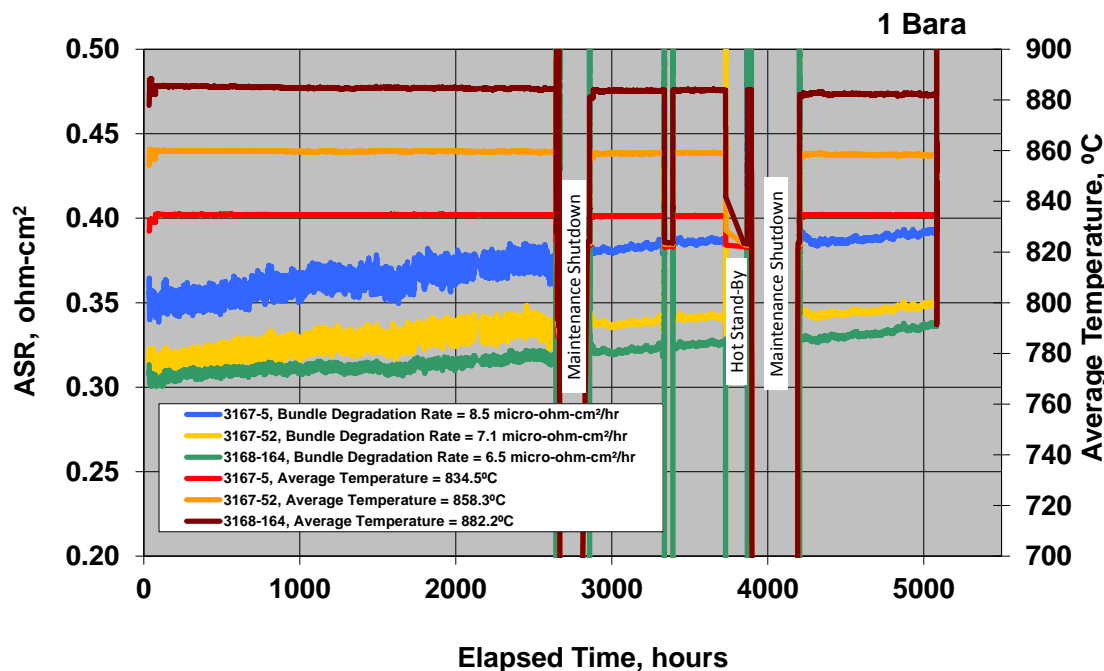
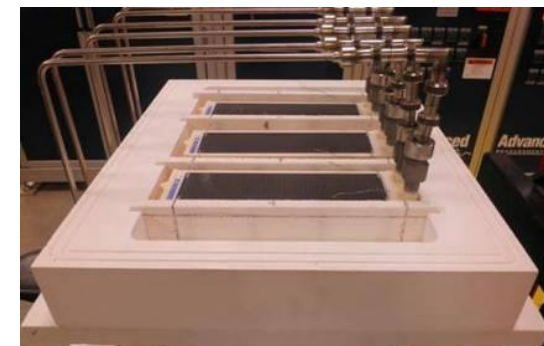
Cathode Rp Comparison (900°C, 925°C)



Triple bundle test with candidate cathodes showing improved durability trends

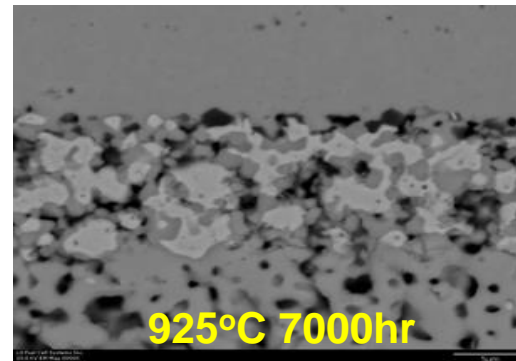
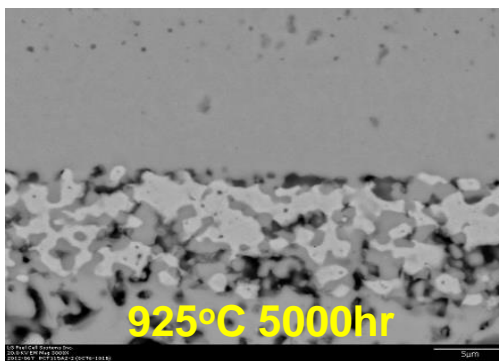
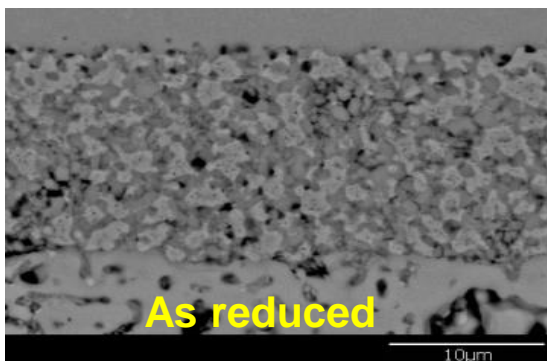
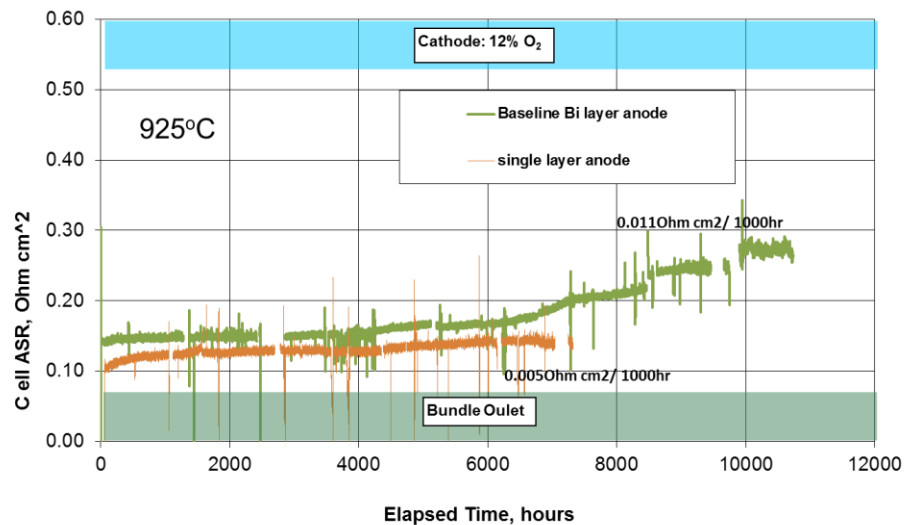
- Only change from baseline cell technology was the cathode
- Rates consistent with cathode degradation studies
- Projects to a 2-½ year life across block temp. profile and for block starting ASR
- Further durability extension with anode and interconnect changes

| Time = | 5082 hours | Bundle 1: 3167-5 | Bundle 2: 3167-52 | Bundle 3: 3168-164 | |
|-------------------------|------------|---------------------|----------------------|-----------------------|------------------------------|
| Average Temperature | | 834.5 | 858.3 | 882.2 | °C |
| Bundle Degradation Rate | | 0.52% | 0.43% | 0.35% | %Power/1000 hrs |
| Bundle ASR | | 0.0085 | 0.0071 | 0.0065 | ohm-cm ² /1000 hr |



Single Layer Anode Selected for EIS Business Phase

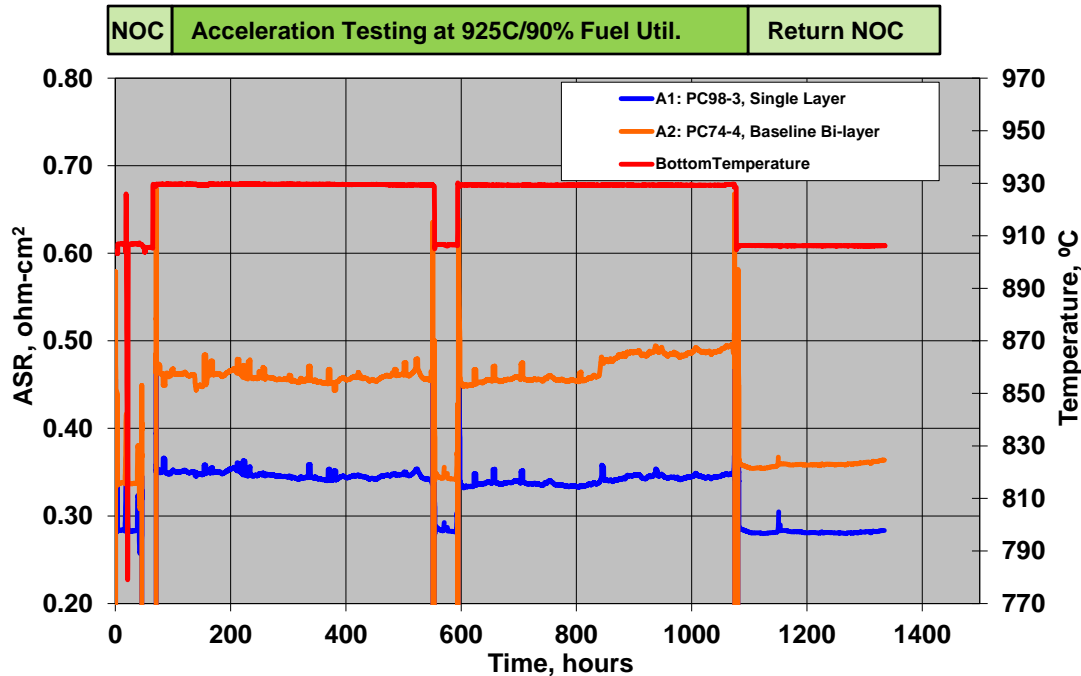
- Exhibits more uniform microstructure than baseline bi-layer at similar test times
- Accelerated testing being developed for quicker screening of final anode compositions



H₂: 14%, CO:7.5%, H₂O: 50%, CO₂: 25.5%, N₂: 3%

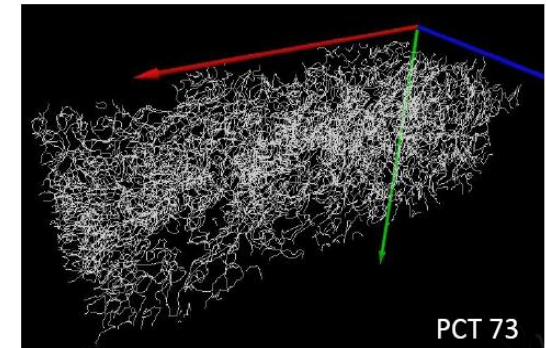
Single Layer Anode Showing Improved Durability

- Lower ASR change and degradation rate after accelerated testing
- The results were repeated

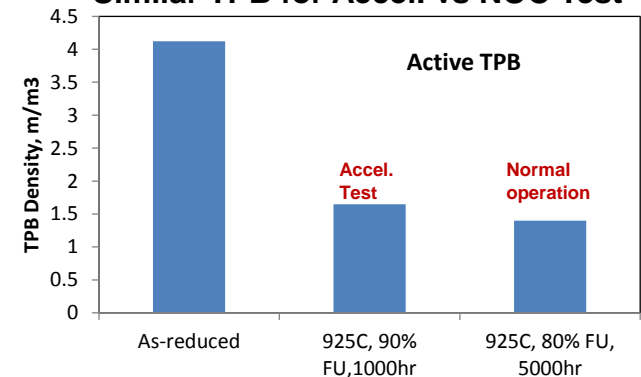


| | Δ ASR, ohm-cm ² (before/after accel.) |
|-------------------------|--|
| Baseline Bi-layer anode | 0.018 |
| Single layer anode | -0.003 |

TPB was generated from 3D database



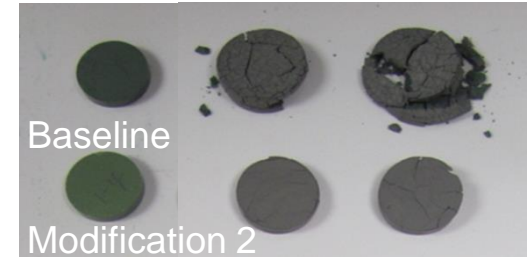
Similar TPB for Accel. vs NOC Test



Improved Redox Tolerance is Sought for Anode Protection Simplification

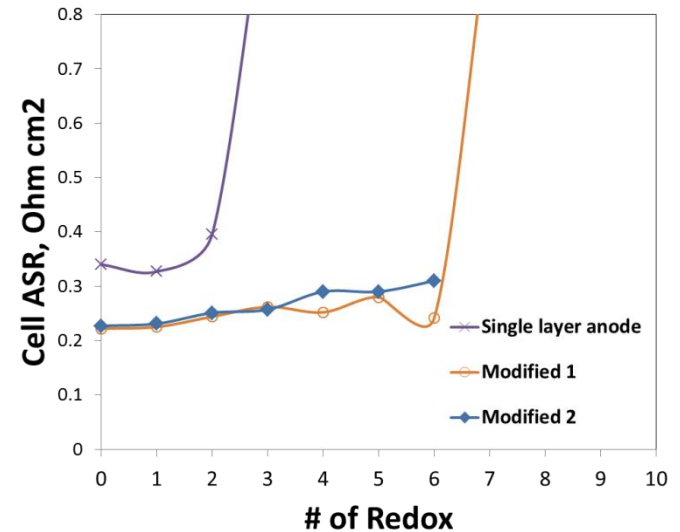
- Tolerate low probability of occurrence emergency events
- Anodes tested
 - Baseline single layer anode
 - Modified 1: composition modification
 - Modified 2: microstructure optimization
- Screening tests
 - Pellet test
 - Single cell test

• Pellet test: 5 redox cycles for different pellets



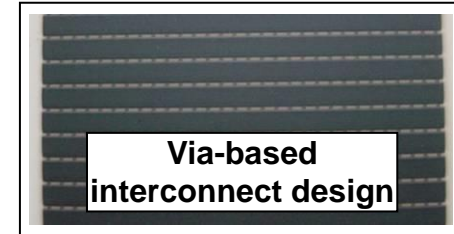
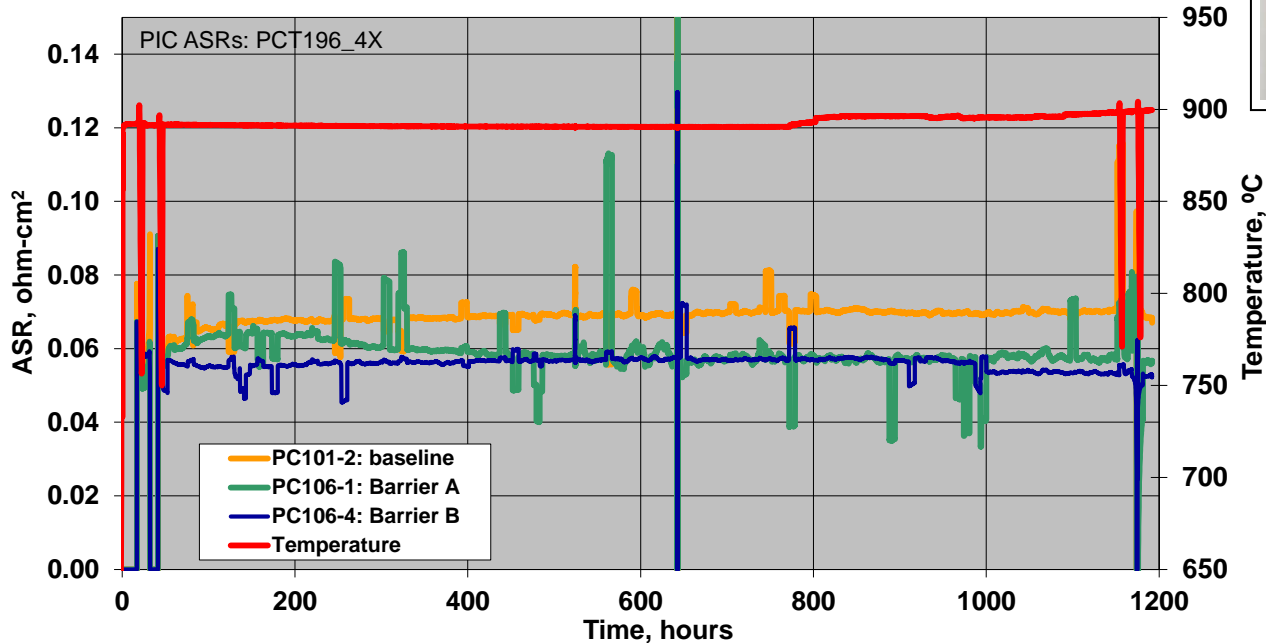
• Single cell test

• Redox Cycle: 900C, 3 hrs oxidation, N₂ purge



Primary Interconnection Modification to Further Reduce Materials Migration

- Barrier layer modification does not increase the ASR
- Longer-term testing at most aggressive bundle conditions to accelerate mechanisms
- Post-test evaluations versus time to confirm benefits

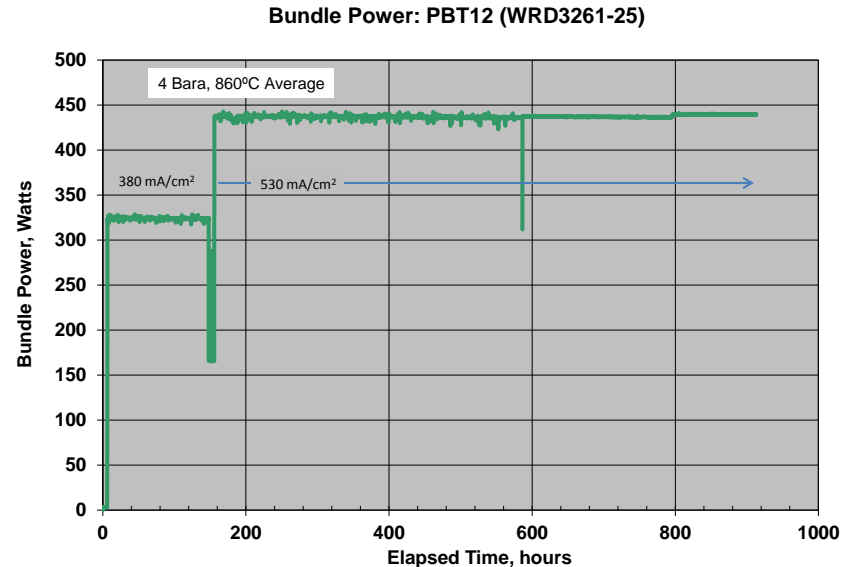
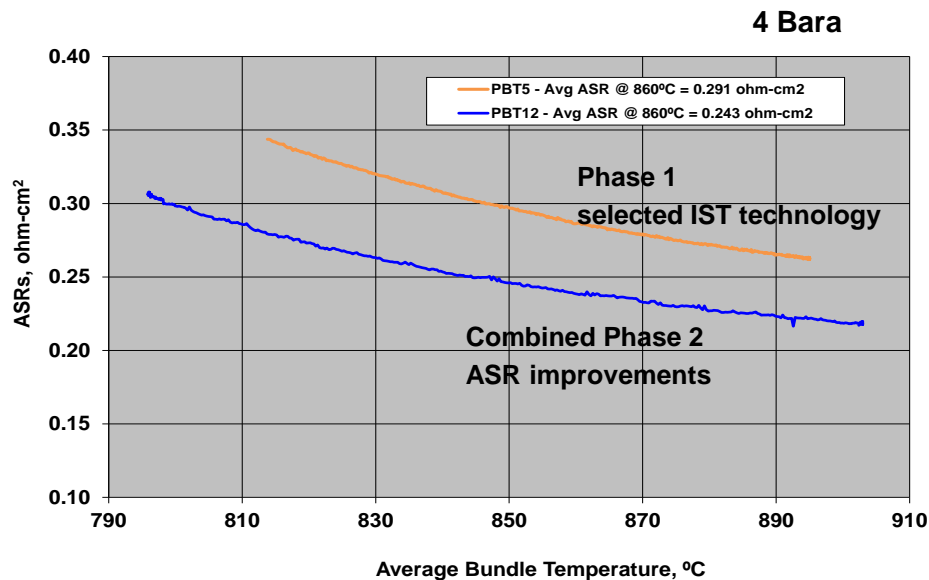


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Lower ASR technology demonstrated at bundle-scale

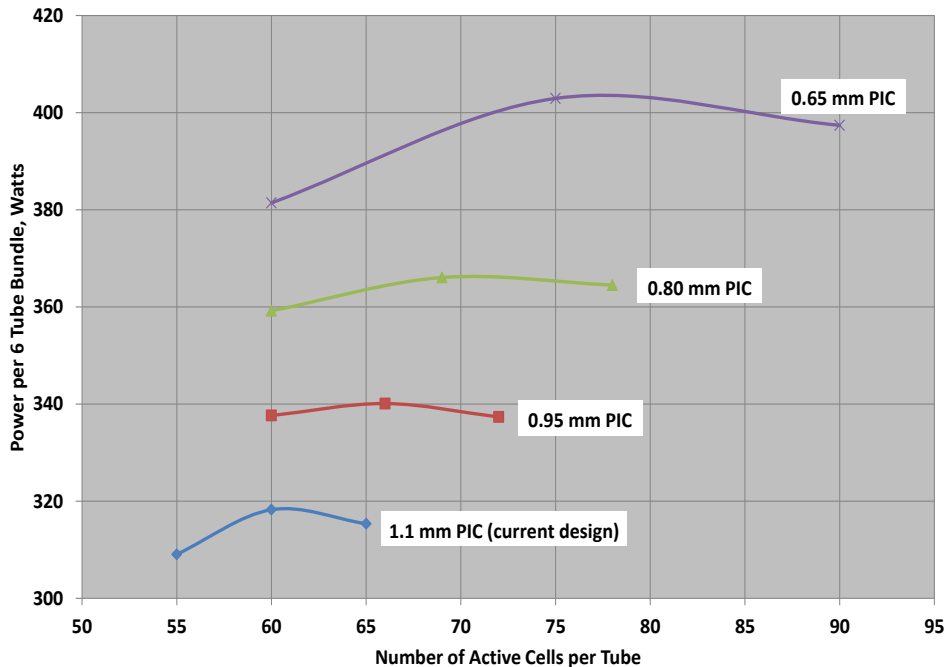
- ASR reduction at 4 bar of >0.04 ohm-cm²
- Meets ASR targets for initial products
- Optimized LSM compositions (lower R_p)
- Modified primary interconnect design
- Single layer anode
- Durability testing at higher current density design point



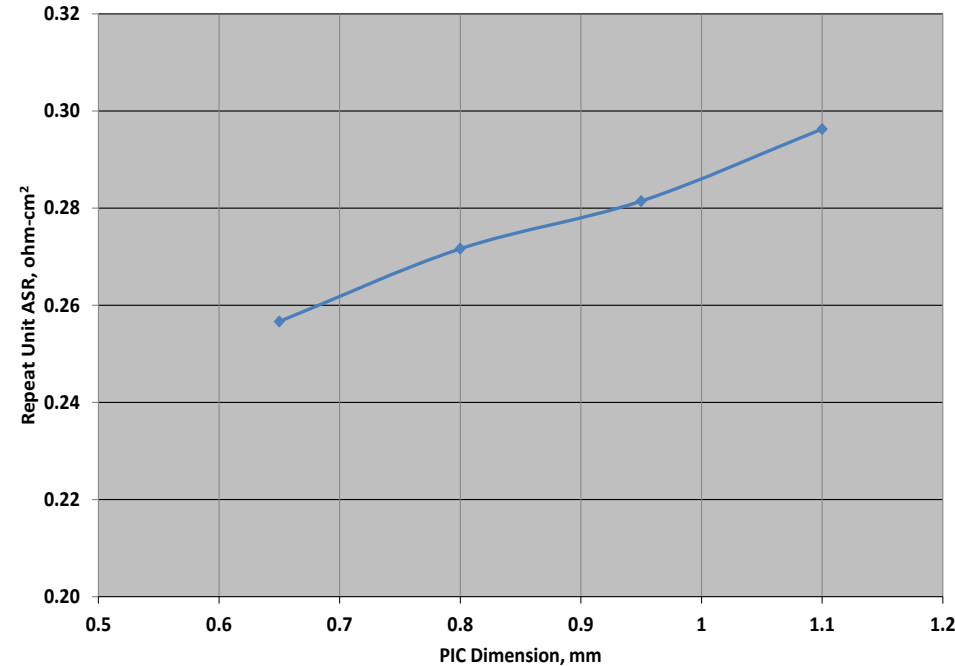
Print pattern changes to optimize power output

- Smaller primary interconnect dimension has lower ASR contribution
- Decreased cell pitch gives a lower in-plane resistance
- Lower ASR combined with increased active area per tube gives a *potential* increase in power output up to 26%
- Printing trials with 0.95 mm PIC in process

Bundle Power for Smaller PIC Dimension
(Constant Efficiency)

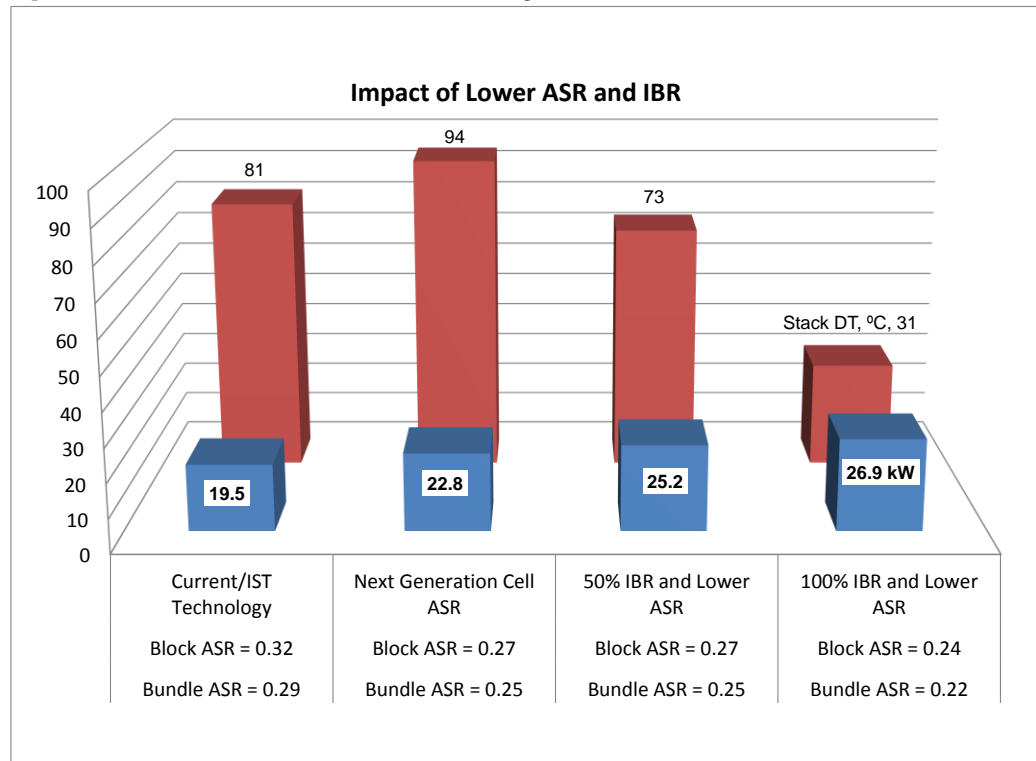


Repeat Unit ASR Reduction vs PIC Dimension
(Constant Efficiency)



Increasing In-Block-Reforming (IBR) to increase power density and manage Block ΔT

- Thermal integration enables operation at higher current density while maintaining reasonable stack temperature
- Higher power density means less stack, smaller package, reduced size of BOP components
 - Single turbogenerator serves greater kW
- May also minimize stack temperature extremes at the hot and cold end which may be beneficial for performance and durability considerations.

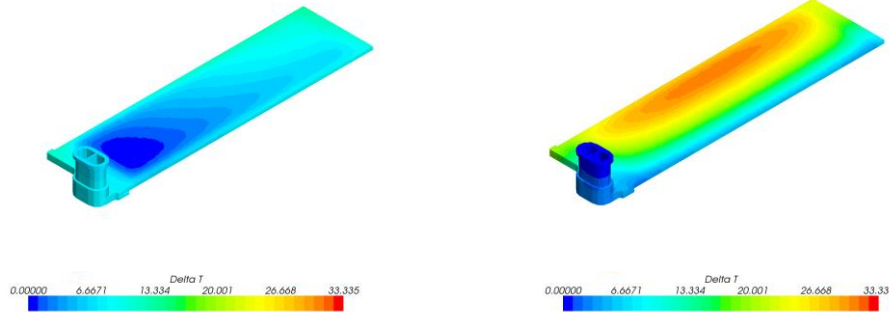


Block ΔT

**Block Power
(5 strips)**

IBR development activities addressing Thermal Stresses and Carbon Avoidance

- Multi-physics modeling



All reforming within bundle

Current approach: reforming external to bundle

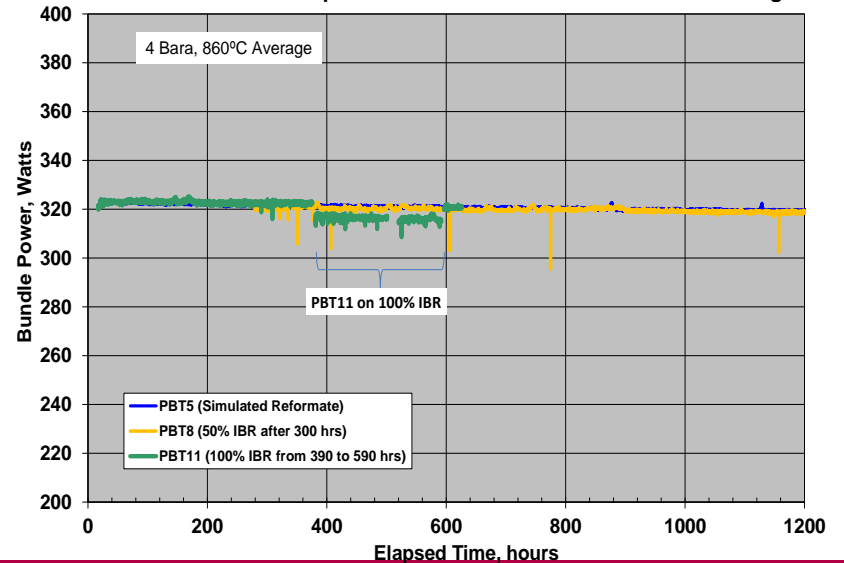
Lower thermal gradients with incorporation of in-block reforming (inlet substrate shown)

- Bundle test at 50% and 100% IBR performed

- Nearly full conversion of CH_4
- Lower power at 100% IBR from Nerst potential difference

| Case | Bundle Power | Bundle ΔT |
|-----------|--------------|-------------------|
| Reformate | 322 W | 20°C |
| 50% IBR | 320 W | 12°C |
| 100% IBR | 316 W | 6°C |

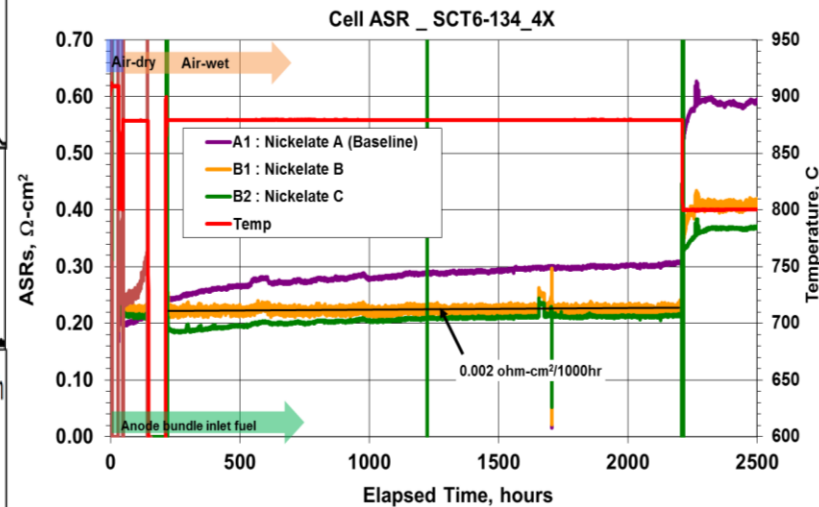
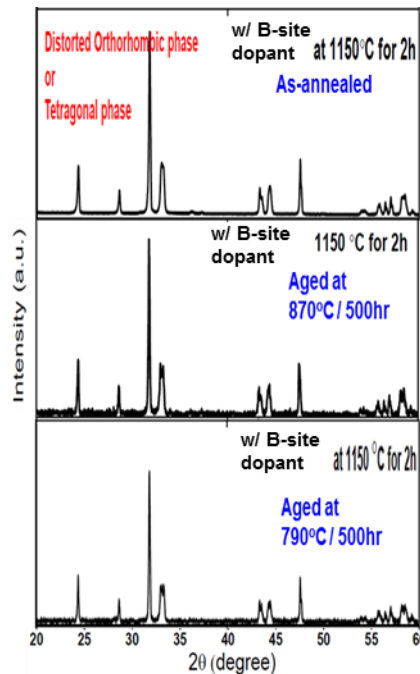
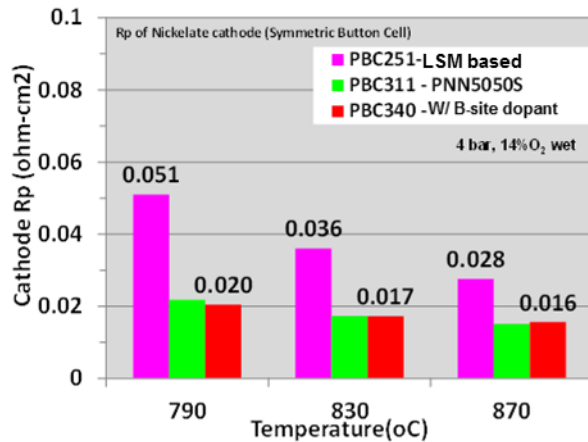
Bundle Power Comparison with and without In Block Reforming



Further Reduction in Cell ASR using Nickelate Cathodes

- Phase instability under operating conditions has been major issues
- Technical approaches to improve nickelate phase stability
 - A-site doped $\text{Pr}_2\text{NiO}_{4+\delta}$
 - $(\text{Pr}_{0.25}\text{Nd}_{0.75})$ A-site ratio is phase stable¹, $(\text{Pr}_{0.5}\text{Nd}_{0.5})$ exhibits instability
 - Addition of B-site dopants provides phase stability for A-site $(\text{Pr}_{0.5}\text{Nd}_{0.5})$

Nickelate provides ~0.02 ohm-cm² lower ASR than most favorable LSM-based cathode



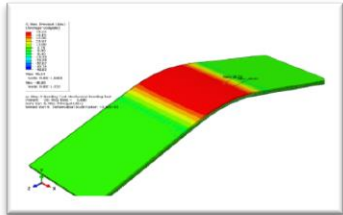
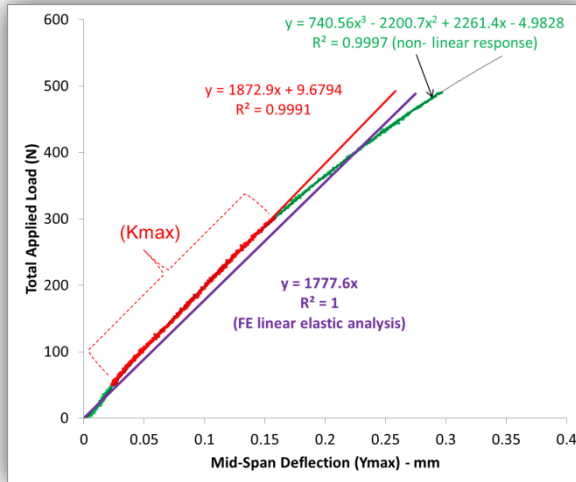
1. Advances in Solid Oxide Fuel Cells III, Ceramic Eng. and Sci. Proc., 28(4) 2008.

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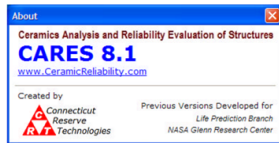
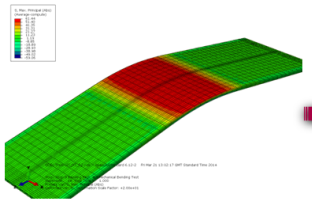
FEA Validation and CARES Prediction

FE Stress Modelling: Validation at RT



| MMA Substrate Gen 2 | Ratios (Exp./FE) K_{max} (N-mm) |
|--|--------------------------------------|
| Bare Substrate (avg. strength from 30 test) | 1804/1777.6 = 1.01 |
| Glassed Substrate (120 μ m thick glass layer and avg. strength from 6 test) | 1831/2102.5 = 0.87 |
| Full Printed Substrate (avg. strength from 15 test) | 2504/2726.5 = 0.92 |

CARES Prediction: 4pt bend test at RT



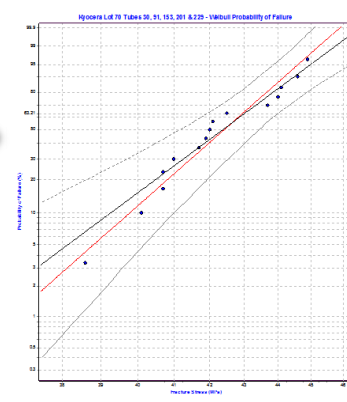
$$B = \left[\left(\frac{\sigma_1}{\sigma_0} \right)^m V_1 \right] + \left[\left(\frac{\sigma_2}{\sigma_0} \right)^m V_2 \right] + \left[\left(\frac{\sigma_3}{\sigma_0} \right)^m V_3 \right] + \dots$$

$$R = \exp(-B)$$

$$P_f = 1 - R$$

$$P_i = 1 - e^{-V \left(\frac{\sigma_{max}}{\beta} \right)^m}$$

$$P_f = 1 - \prod_{i=1}^N (1 - P_i)$$



• **Input from 4pt bend test on MMA Substrate :**

• $\sigma_0 = 57.48$, $m = 16.48$

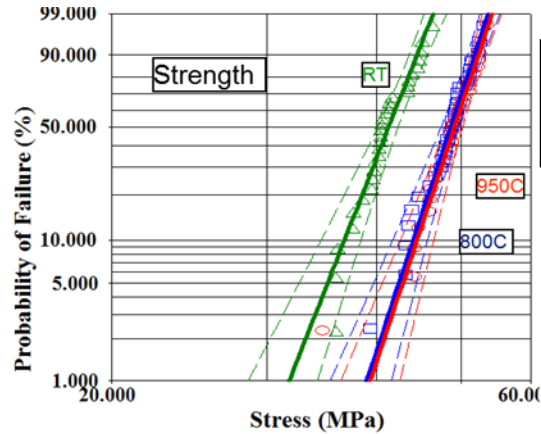
• **CARES Output:**

• P_f , CARES prediction = 63%

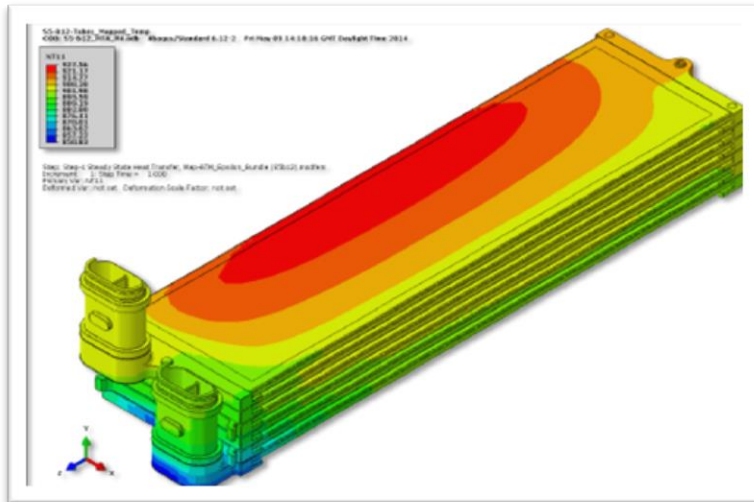
• P_f , expected = 63.2% (Good Agreement)

Very Low P_f of Substrate under Operating conditions (Fast fracture)

- Conservative assumptions of Weibull parameters – used RT values under 2 conditions
 - Tube specification (MoR= 29MPa, m=15)
 - Actual Tube MOR (MoR= 1.31MPa, m = 14.98)
- Bundle thermal boundary conditions mapped in ABAQUS.
- Peak stresses for substrate 2 of top bundle in strip 5 (worst case)



| Temperature | Strength, MPa (Pf=63.2%) | Weibull Modulus |
|-------------|--------------------------|-----------------|
| room temp. | 42.3 | 16.2 |
| 800C | 49.5 | 19.3 |
| 950C | 50 | 19.2 |



| MMA Substrate (Tube #) | Max. Stress (MPa) | Pf (%), Actual | Pf (%), Tube Specification |
|------------------------|-------------------|----------------------|----------------------------|
| 1 | 6.40 | 0.86e ⁻¹¹ | 0.18e ⁻¹¹ |
| 2 | 15.27 | 0.51e ⁻⁸ | 0.107e ⁻⁵ |
| 3 | 9.10 | 0.13e ⁻¹⁰ | 0.27e ⁻⁸ |
| 4 | 7.40 | 0.10e ⁻⁹ | 0.25e ⁻⁷ |
| 5 | 5.95 | 0.95e ⁻¹¹ | 0.19e ⁻⁸ |
| 6 | 7.54 | 0.16e ⁻⁹ | 0.33e ⁻⁷ |

Low P_f of Substrate under Normal Operating Conditions (Slow fracture)

- Conservative assumptions of Weibull parameters – used RT values under 2 conditions
- Used actual high temperature SGC parameters from ORNL

Future Work:

- FEA for dense parts+ CARES prediction for a full strip
- Low risk of failure of dense parts as strength 4X substrate and similar SCG parameters and $>K_{Ic}$
- Block transient stress states

SCG parameters used for Analysis

1. Weibull & Fatigue Parameters:

$$m = 14.98$$

$$\sigma_{0V} = 58.92 \text{ MPa mm}^{3/m}$$

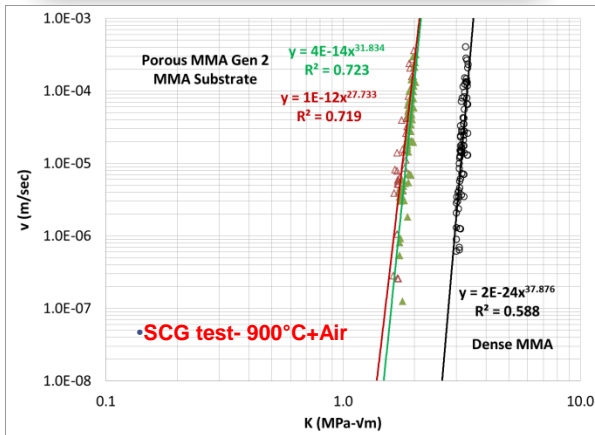
$$N = 35.52$$

$$A = 4e^{-13}$$

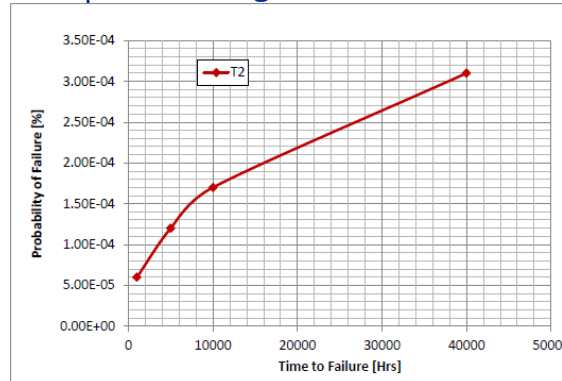
$$K_{Ic} = 2.08 \text{ MPa m}^{1/2}$$

$$Y = 2.3$$

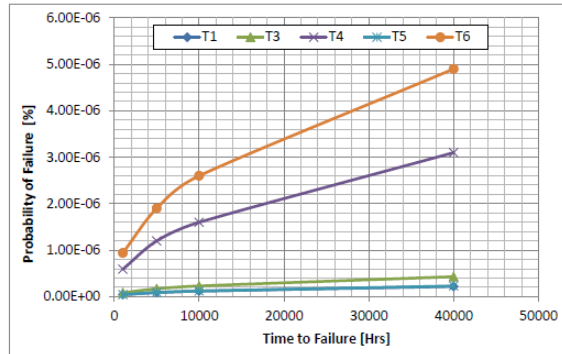
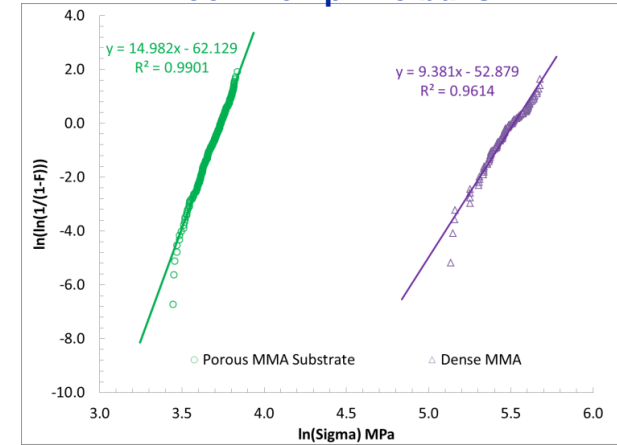
$$B = \frac{2}{AY^2 K_{Ic}^{N-2} (N-2)} = 0.615 \text{ MPa}^2 \text{ sec}$$



P_f in 10^{-4} range for substrate 2



Room Temp. Weibulls



| | MoR (MPa) | m |
|------------|-----------|-------|
| Porous MMA | 41.31 | 14.98 |
| Dense MMA | 248.61 | 9.38 |

Phase 2 Block Test: Post-test Reliability Assessment

Approach: Measure RT 4-pt and compare to bare substrate of identical lot.

- The ratio of Tested Substrate: As-rec'd Bare Substrate is ~1.3-1.5, typical of ratio for as-processed substrates
- This indicates little or no loss in strength over the nominal 3000 hours of operation.

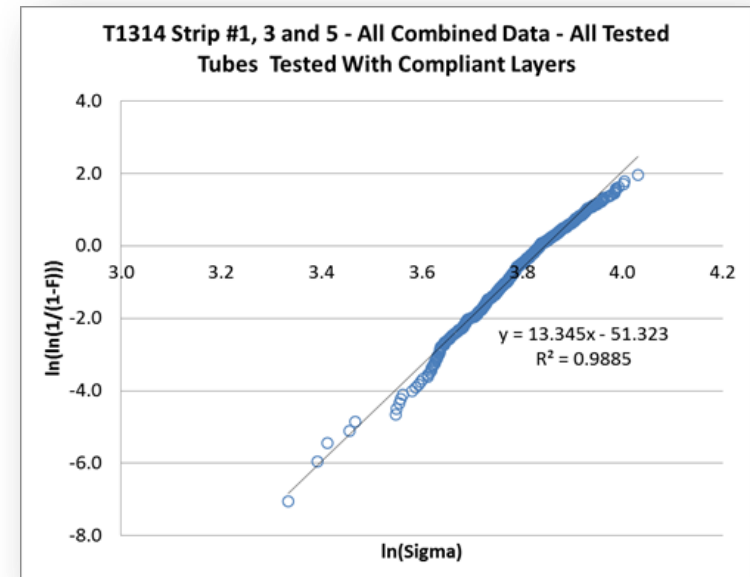
Mechanical Properties

- Fracture can start from surface defect as well as from volume imperfection.
- All the data (~600) from Strip 1, 3 and 5 put together show a good linear fit.

| | MoR (MPa) | m |
|-----------|-----------|-------|
| Post-test | 46.76 | 13.43 |

| Strip No. | Lot No. | No. of Test Specimens | Strength Ratio (\pm 95% Conf. Int.) |
|-----------|---------|-----------------------|--|
| 1 | 22 | 186 | 1.32 \pm 0.019 |
| 1 | 32-2 | 19 | 1.32 \pm 0.048 |
| 3 | 32-1 | 196 | 1.46 \pm 0.014 |
| 5 | 32-2 | 36 | 1.39 \pm 0.15 |
| 5 | 24 | 132 | 1.40 \pm 0.14 |
| 5 | 25 | 33 | 1.53 \pm 0.07 |

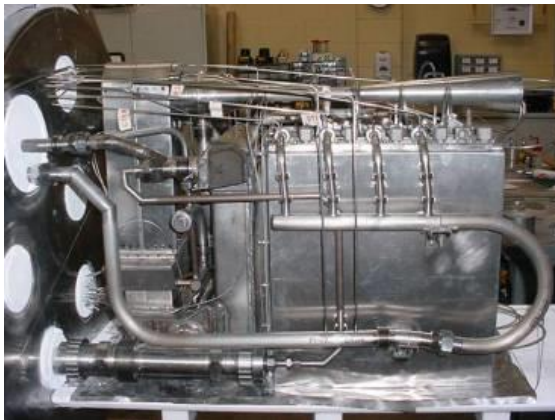
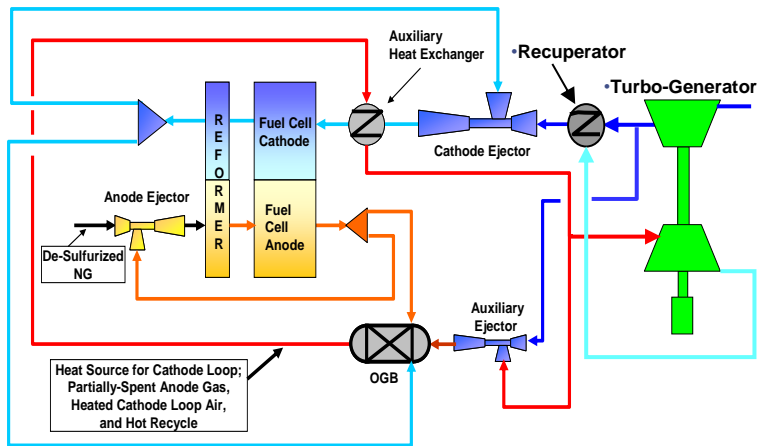
(Mix of Gen1 and Gen2 substrates)



Outline

- LGFCS Business Activities - 220 kW test
- Degradation Mechanisms and Mitigation
 - Cathode
 - Anode
 - Primary Interconnect
- Cell-Stack changes for lower cost
- Strip Reliability
 - Probability of failure predictions
 - Residual strength of substrates
- **Block Testing Update**

Block Testing Matching Product Cycle, Components and Operating Conditions



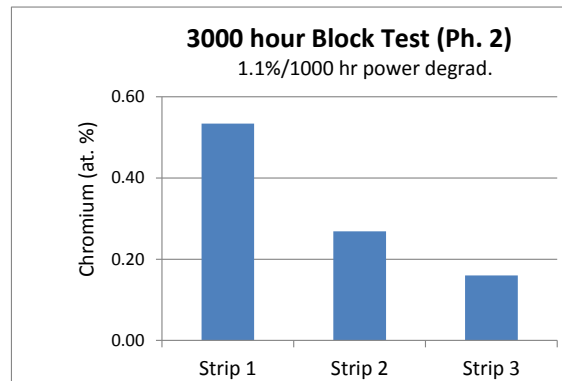
- Initial design of block testing rigs
- Representative of cycle and components
- Not packaged for product



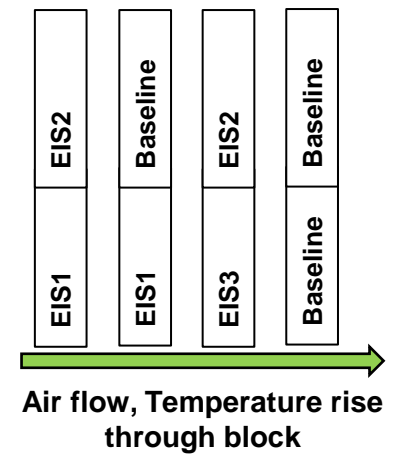
- One rig converted to match IST block design
- Allows testing of 3 blocks
- Fully representative of product

3 Block Tests Supported by Current Program

- Two 15 kW tests – original block design
 - Screening of cathode technology
 - 1st test: Chromium mitigation, pipeline nat. gas and SCSO desulfurization (started July 2014)
 - 2nd test: higher Chromium sources, pipeline nat. gas (starting Aug 2014)
 - Similar Cr content as Phase 1 and Phase 2 block tests

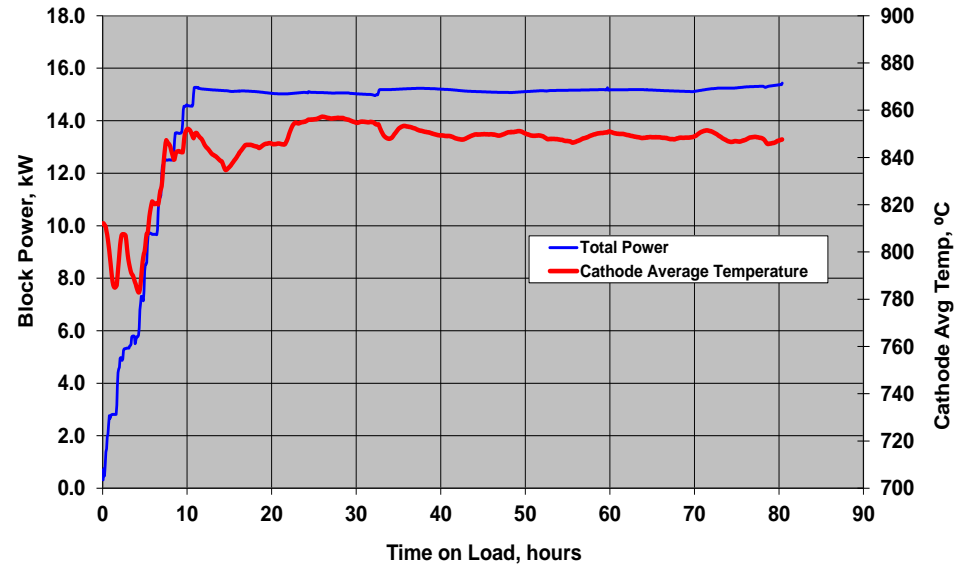
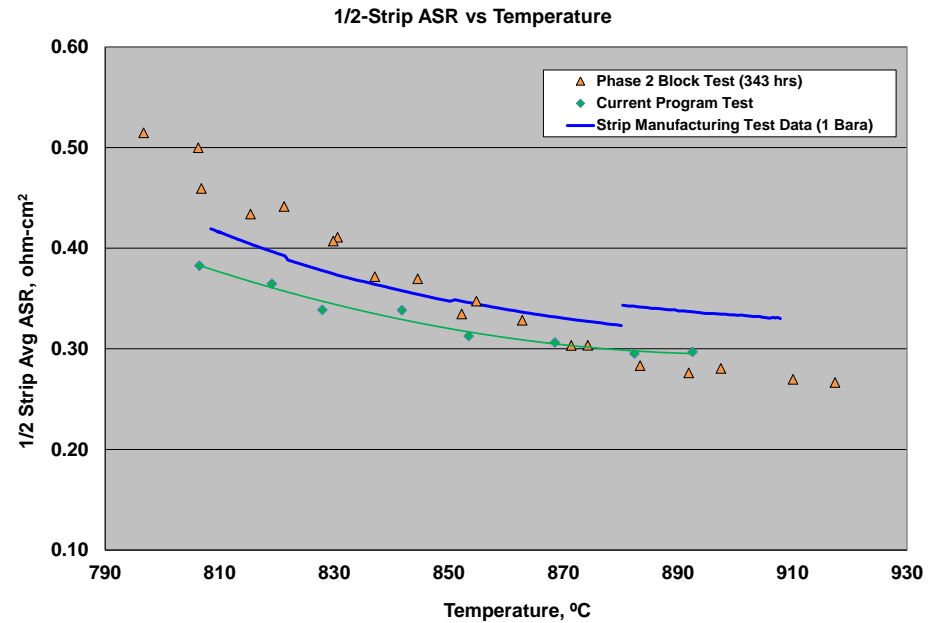


- 3rd 4-strip test of combined cell technology for lower ASR and improved durability
 - expected <0.75%/1000 hours
 - Single layer anode, alternate cathode, primary interconnect redesign



Current Phase Block Test #1

- 4 Strip test with EIS cathode candidates
- 15.4 kW target value achieved
- ASR improved over Phase 2 test, especially at lower temp.
- Problems with BOP forced early shutdown
 - NG-SCSO connectivity
 - Air compressor failure



Conclusion

- **Cell and stack developments supported by SECA are moving into 220 kW-scale system integration testing**
- **Degradation rates being reduced, further verification through accelerated and longer-term testing across testing platforms**
- **Active layer materials in final screening for inclusion in next business phase of system field testing**
- **In-block reforming coupled with lower ASR cell technology provides significant cost reductions – focus of next Phase.**

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